

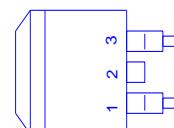
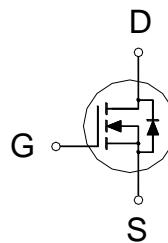
NIKO-SEM**N-Channel Logic Level Enhancement
Mode Field Effect Transistor****PP4B10BS**

TO-263

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	4.2mΩ	134A



1.GATE
2.DRAIN
3.SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	134	A
	$T_C = 100^\circ\text{C}$		94	
Pulsed Drain Current ¹		I_{DM}	370	
Avalanche Current		I_{AS}	20	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	200	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	166	W
	$T_C = 100^\circ\text{C}$		83	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 175	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		0.9	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.7	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}, T_J = 55^\circ\text{C}$			10	

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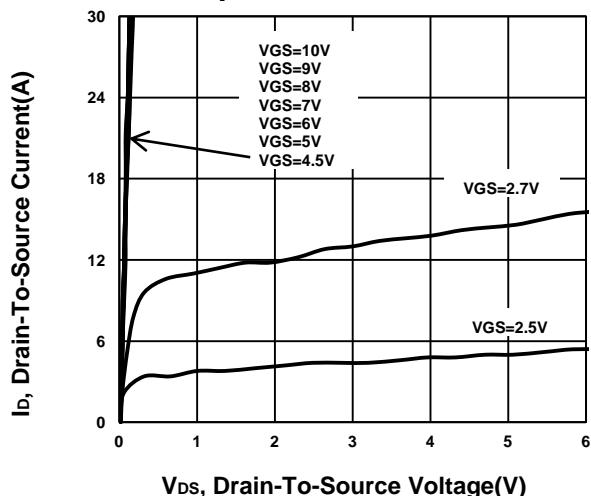
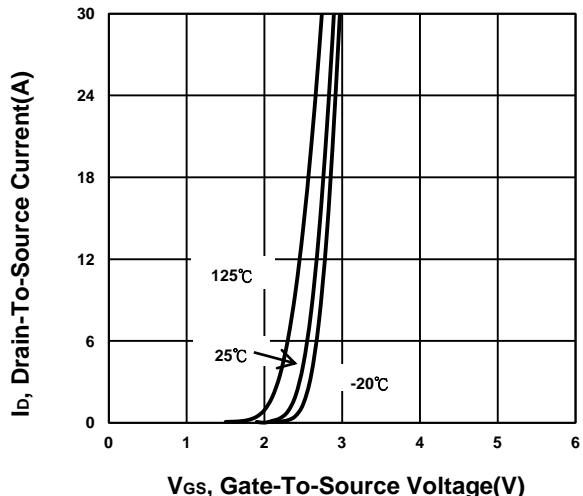
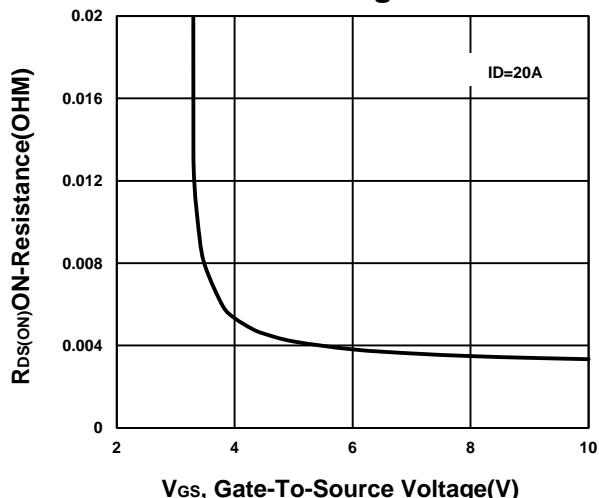
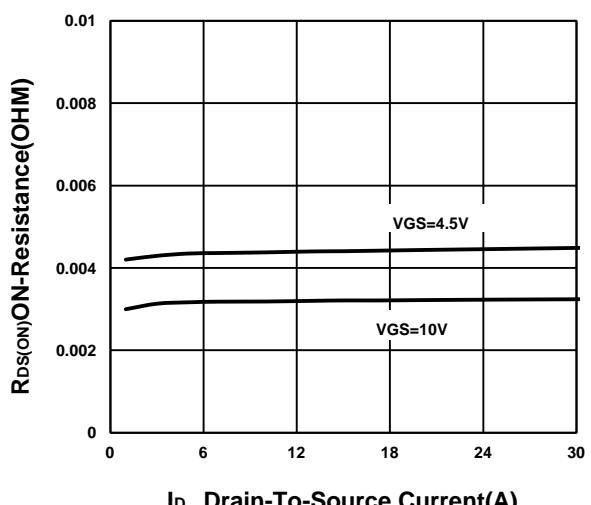
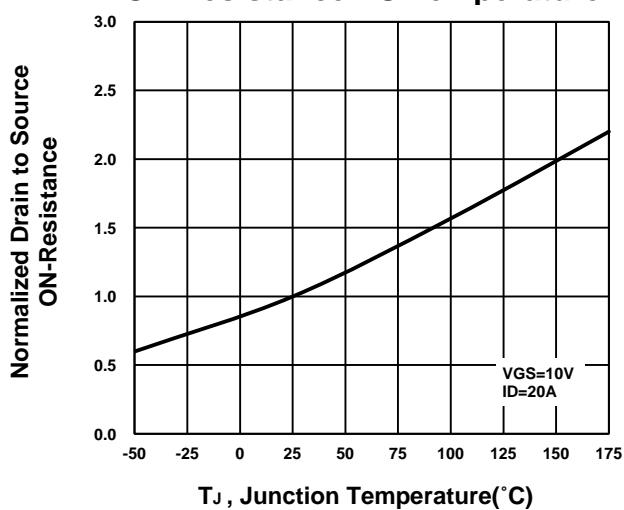
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 20A$	3.4	4.2	$m\Omega$
		$V_{GS} = 4.5V, I_D = 20A$	4.7	5.6	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 20A$	68		S
DYNAMIC					
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 50V, f = 1MHz$	4242		pF
Output Capacitance	C_{oss}		744		
Reverse Transfer Capacitance	C_{rss}		9		
Gate Resistance	R_g		1		
Total Gate Charge ²	Q_g	$V_{DS} = 50V, V_{GS} = 10V, I_D = 20A$	88		nC
Gate-Source Charge ²	Q_{gs}		9.8		
Gate-Drain Charge ²	Q_{gd}		25		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 50V$ $I_D \approx 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$	21		nS
Rise Time ²	t_r		63		
Turn-Off Delay Time ²	$t_{d(off)}$		109		
Fall Time ²	t_f		133		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)					
Continuous Current	I_S	$I_F = 20A, V_{GS} = 0V$		131	A
Forward Voltage ¹	V_{SD}			1.2	V
Reverse Recovery Time	t_{rr}		61		nS
Reverse Recovery Charge	Q_{rr}		88		nC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

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Output Characteristics**Transfer Characteristics****On-Resistance VS Gate-To-Source Voltage****On-Resistance VS Drain Current****On-Resistance VS Temperature****Capacitance Characteristic**